TOSHIBA Photocoupler GaAs Ired & Photo-Transistor

TLP731,TLP732

Office Machine Household Use Equipment Solid State Relay Switching Power Supply

The TOSHIBA TLP731 and TLP732 consist of a photo-transistor optically coupled to a gallium arsenide infrared emitting diode in a six lead plastic DIP package.

 $\mathrm{TLP732}$ is no–base internal connection for high–EMI environments.

- Collector-emitter voltage: 55V (min.)
- Current transfer ratio: 50% (min.) Rank GB: 100% (min.)
- UL recognized: UL1577, file No. E67349
- BSI approved: BS EN60065: 1994

Certificate No. 6617 BS EN60950: 1992 Certificate No. 7366 Isolation voltage: 4000V_{rms} (min.)

• Option (D4) type

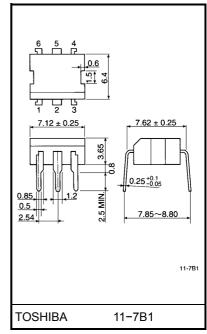
VDE approved: DIN VDE0884 / 08.87,

Certificate No. 65640

Maximum operating insulation voltage: 630VPK Highest permissible over voltage: 6000VPK

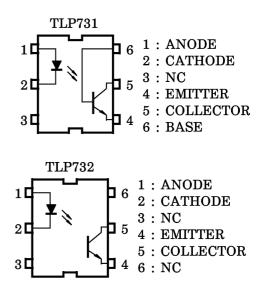
(Note) When a VDE0884 approved type is needed, please designate the "Option (D4)"

		7.62mm pich	10.16mm pich
		standard type	(LF2) type
٠	Creepage distance	: 7.0mm (min.)	8.0 mm (min.)
	Clearance	: 7.0 mm (min.)	8.0 mm (min.)
	Insulation thickness	: 0.5 mm (min.)	0.5 mm (min.)



Weight: 0.35 g

Pin Configurations (top view)



Maximum Ratings (Ta = 25°C)

	Characteristic	Symbol	Rating	Unit
	Forward current	١ _F	60	mA
	Forward current derating (Ta ≥ 39°C)	ΔI _F / °C	-0.7	mA / °C
	Peak forward current (100µs pulse, 100pps)	I _{FP}	1	А
LED	Power dissipation	PD	100	mW
	Power dissipation derating (Ta ≥ 25°C)	ΔP _D /°C	-1.0	mW / °C
	Reverse voltage	V _R	5	V
	Junction temperature	Tj	125	°C
	Collector-emitter voltage	V _{CEO}	55	V
	Collector-base voltage (TLP731)	V _{CBO}	80	V
	Emitter-collector voltage	V _{ECO}	7	V
ctor	Emitter-base voltage (TLP731)	V _{EBO}	7	V
Detector	Collector current	Ι _C	50	mA
	Power dissipation	Pc	ΔI _F / °C -0.7 mA I _{FP} 1 r P_D 100 r ΔP_D / °C -1.0 mV V_R 5 r Tj 125 r V _{CEO} 55 r V _{EBO} 7 r P _C 150 r P _C 150 r ΔP _C / °C -1.5 mV T _j 125 r T _j 125 r N 50 r P _C 150 r T _j 125 r T _j 255~125 r T _{opr} -55~100 r P _T 260 r	mW
	Power dissipation derating (Ta ≥ 25°C)	ΔP _C / °C	-1.5	mW / °C
	Junction temperature	Tj	125	°C
Storag	e temperature range	T _{stg}	-55~125	°C
Opera	ting temperature range	T _{opr}	-55~100	°C
Lead s	oldering temperature (10s)	T _{sol}	sol 260	
Total p	backage power dissipation	PT	250	mW
Total p	backage power dissipation derating (Ta $\ge 25^{\circ}$ C)	ΔP _T / °C	-2.5	mW / °C
Isolatio	on voltage (AC, 1min., R.H.≤ 60%)	BVS	4000	V _{rms}

Recommended Operating Conditions

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V _{CC}	_	5	24	V
Forward current	١ _F		16	25	mA
Collector current	Ι _C	_	1	10	mA
Operating temperature	T _{opr}	-25		85	°C

Individual Electrical Characteristics (Ta = 25°C)

	Characteristic		Symbol	Test Condition	Min.	Тур.	Max.	Unit
LED	Forward voltage		VF	I _F = 10mA	1.0	1.15	1.3	V
	Reverse current		I _R	V _R = 5V	_	_	10	μA
	Capacitance		CT	V = 0, f = 1MHz	_	30	-	pF
	Collector-emitter breakdown voltage		V _{(BR)CEO}	I _C = 0.5mA	55	-		V
	Emitter-collector breakdown voltage		V _{(BR)ECO}	I _E = 0.1mA	7	_		V
	Collector-base breakdown voltage	(TLP731)	V _{(BR)CBO}	I _C = 0.1mA	80	_	_	V
	Emitter-base breakdown voltage	(TLP731)	V _{(BR)EBO}	I _E = 0.1mA	7	-		V
Detector	Collector dark current		ICEO	V _{CE} = 24V	—	10	100	nA
Dete			ICEO	V _{CE} = 24V, Ta = 85°C	_	2	50	μA
	Collector dark current	(TLP731)	I _{CER}	V _{CE} = 24V, Ta = 85°C R _{BE} = 1MΩ	_	0.5	10	μA
	Collector dark current	(TLP731)	I _{CBO}	V _{CB} = 10V	_	0.1	_	nA
	DC forward current gain	(TLP731)	h _{FE}	$V_{CE} = 5V, I_{C} = 0.5mA$	—	400	_	—
	Capacitance collector to emitter)	C _{CE}	V = 0, f = 1MHz	_	10	_	pF

Coupled Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit	
Current transfer ratio	I _C / I _F	I _F = 5mA, V _{CE} = 5V	50	_	600	0/	
	IC / IF	Rank GB	100	—	600	- %	
Saturated CTR	I _C / I _{F (sat)}	I _F = 1mA, V _{CE} = 0.4V Rank GB	_	60	_	%	
			30	—	—		
Base photo-current (TLP731)	I _{PB}	I _F = 5mA, V _{CB} = 5V	—	10	—	μA	
		I _C = 2.4mA, I _F = 8mA	—	—	0.4		
Collector–emitter saturation voltage	V _{CE (sat)}	I _C = 0.2mA, I _F = 1mA	_	0.2	_	V	
		Rank GB	-	-	0.4		

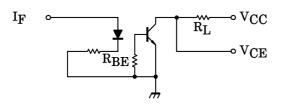
Isolation Characteristics (Ta = 25°C)

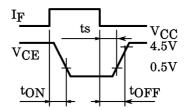
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Capacitance (input to output)	CS	V _S = 0, f = 1MHz	_	0.8	_	pF
Isolation resistance	R _S	V _S = 500V	1×10 ¹²	10 ¹⁴	_	Ω
		AC, 1 minute	4000	_		V _{rms}
Isolation voltage	BVS	AC, 1 second, in oil	_	10000	_	v rms
		DC, 1 minute, in oil	-	10000	-	V _{dc}

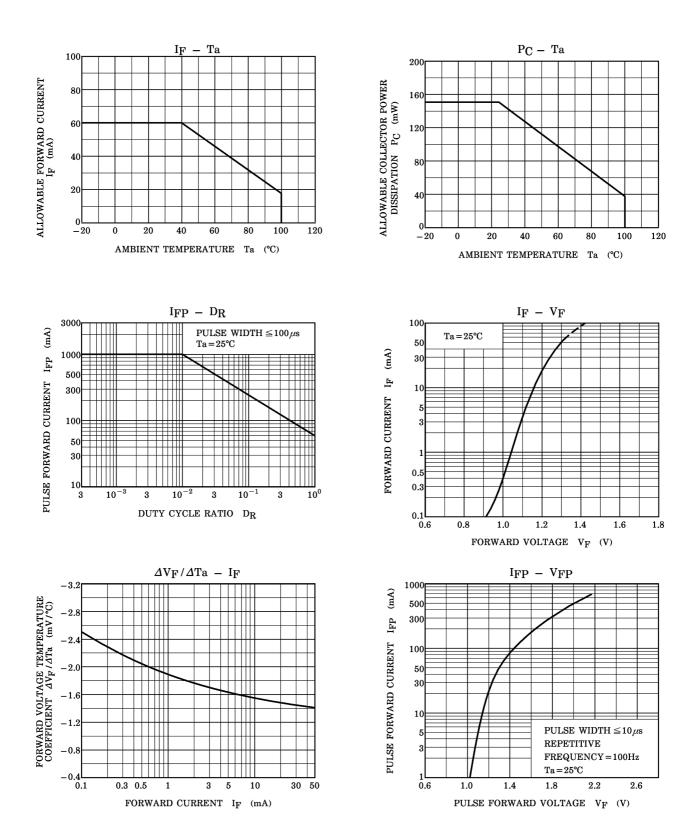
Switching Characteristics (Ta = 25°C)

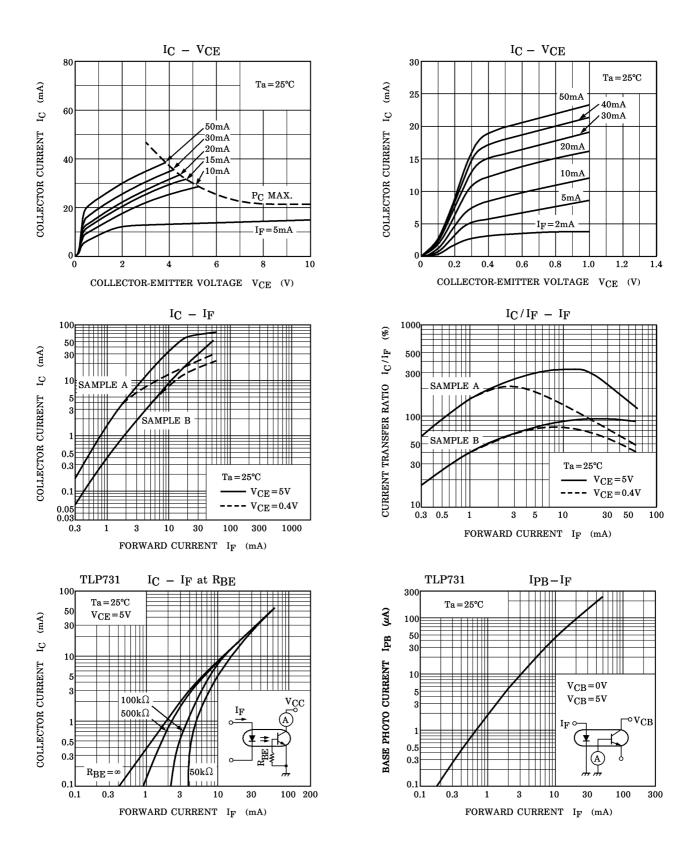
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Rise time	t _r		_	2	—	μs
Fall time	t _f	V _{CC} = 10V, I _C = 2mA	_	3	_	
Turn–on time	t _{on}	$R_L = 100\Omega$	_	3	10	
Turn–off time	t _{off}		_	3	10	
Turn–on time	t _{ON}	R _L = 1.9kΩ (Fig.1)	_	2	_	μs
Storage time	ts	R _{BE} = open	_	15	_	
Turn–off time	t _{OFF}	V _{CC} = 5V, I _F = 16mA	_	25	_	
Turn–on time	t _{ON}	R _L = 1.9kΩ (Fig.1) R _{BE} = 220kΩ (TLP731) V _{CC} = 5V, I _F = 16mA	_	2	_	
Storage time	ts		_	12	_	μs
Turn–off time	t _{OFF}		_	20	—	

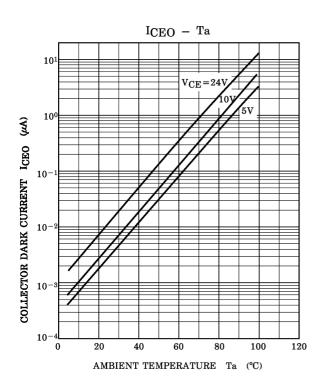
Fig. 1 Switching time test circuit

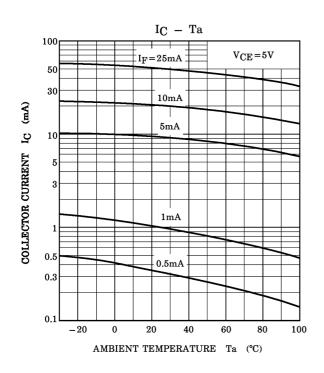


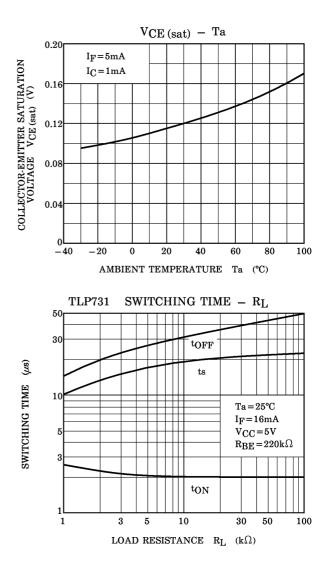


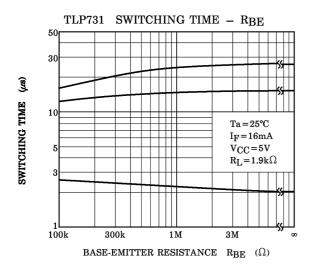


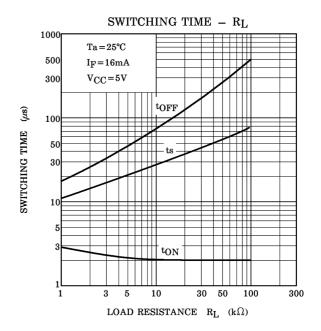












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